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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Shun-ichi FUKUYAMA et al.

Serial No.: 10/630,716

Group Art Unit: 2813

Filed: July 31, 2003

Examiner: Stephen W. Smoot

For: SEMICONDUCTOR DEVICE USING LOW-K MATERIAL AS INTERLAYER  
INSULATING FILM AND ITS MANUFACTURE METHOD

**INFORMATION DISCLOSURE STATEMENT**  
**PURSUANT TO 37 CFR 1.97(c)**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

September 2, 2004

Sir:

Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached Form PTO-1449. A copy of each listed document is attached along with a Notice of Reason of Rejection dated August 10, 2004 (with translation).

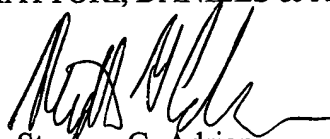
This Information Disclosure Statement is being submitted after issuance of a first official action on the merits and expiration of the three month period following the filing date or the entry of the national stage for the above-captioned application, but prior to issuance of either a final official action or a Notice of Allowance.

The undersigned hereby certifies that each item of information contained in the Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Information Disclosure Statement.

If there are any fees due in connection with the filing of this paper, please charge Deposit  
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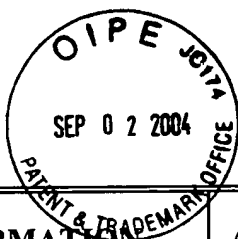
Respectfully submitted,

WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP

A handwritten signature in black ink, appearing to read 'Stephen G. Adrian', with a long horizontal flourish extending to the right.

Stephen G. Adrian  
Attorney for Applicants  
Reg. No. 32,878

Enclosures: PTO-1449, 6 References and Notice of Reason of Rejection dated August 10, 2004



**INFORMATION  
DISCLOSURE  
CITATION  
PTO-1449**

Attv. Docket No. 030860

Serial No. 10/630,716

Applicant(s): Shun-ichi FUKUYAMA et al.

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**U.S. PATENT DOCUMENTS**

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
	AA					
	AB					
	AC					
	AD					
	AE					

**FOREIGN PATENT DOCUMENTS**

Document No.	Date	Country	Translation (Yes or No)
AF 2000-174137	6/2000	Japan	Abstract
AG 2001-274239	10/2001	Japan	Abstract
AH 2000-188331	7/2000	Japan	Abstract
AI 10-144673	5/1998	Japan	Abstract
AJ 2004-31918	1/2004	Japan	Abstract
AK 2003-282703	10/2003	Japan	Abstract

**OTHER DOCUMENTS**

	AL	
	AM	
Examiner	Date Considered	